

**Notic of References Cited**

Application/Control No.

09/871,067

Applicant(s)/Patent Under  
Reexamination  
YAMAGUCHI ET AL.

Examiner

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Art Unit

2874

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-3,944,330	03-1976	Tsunoda et al.	349/152
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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**NON-PATENT DOCUMENTS**

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